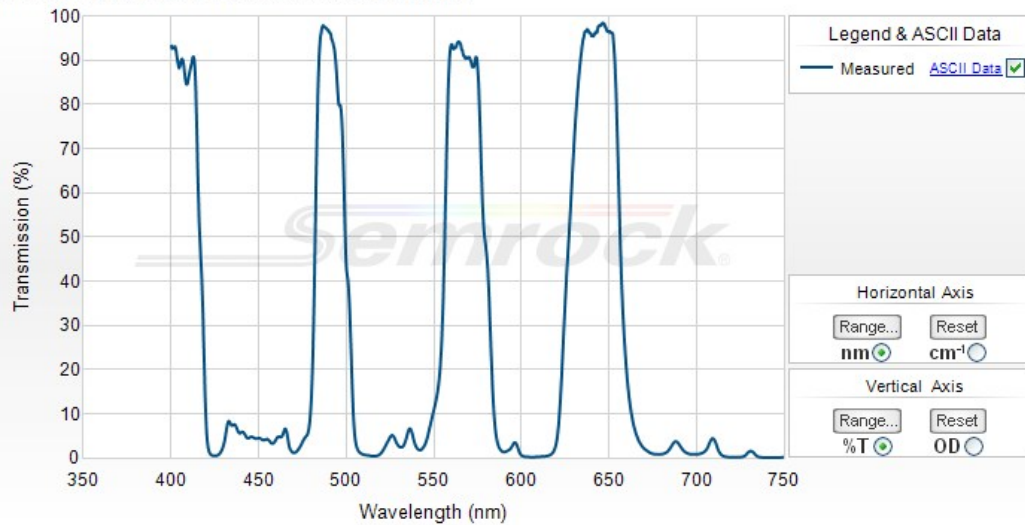


405/488/568/647 nm Yokogawa dichroic beamsplitter

Part Number: Di01-T405/488/568/647-13x15x0.5



Semrock, Inc

3625 Buffalo Road, Suite 6
Rochester, New York 14624

Main Phone: +1 585.594.7050 (worldwide)
Toll Free Phone: 866.736.7625 (866-SEMROCK)
(within US and Canada)

Your filter spectrum may differ slightly from the typical spectrum above, but is certified to meet the optical specifications noted below.



405/488/568/647 nm Yokogawa dichroic beamsplitter

Combining superior performance with exceptional durability, these filters are specifically optimized for use with all Yokogawa CSU spinning-disk scan head system configurations.

Part Number	Size	Price ¹	Stock Status
Di01-T405/488/568/647-13x15x0.5	13 mm x 15 mm x 0.5 mm (unmounted)	\$695	In Stock

This part is not available for custom sizing.

1) US domestic pricing only. If you are ordering from outside the US, please contact your nearest [regional distributor](#) for the correct list price.

Optical Specifications

Specification	Value
Transmission Band 1	Tavg > 80% 405 nm
Reflection Band 1	Ravg > 95% 422 – 473 nm
Edge Wavelength 2	482 nm
Transmission Band 2	Tavg > 80% 488 nm
Reflection Band 2	Ravg > 95% 503 – 545 nm
Edge Wavelength 3	556 nm
Transmission Band 3	Tavg > 80% 561 – 568 nm
Reflection Band 3	Ravg > 95% 586 – 620 nm
Edge Wavelength 4	627 nm
Transmission Band 4	Tavg > 80% 638 – 647 nm
Reflection Band 4	Ravg > 95% 665 – 750 nm

General Filter Specifications

Specification	Value
Laser Wavelength 1	405 nm
Laser Wavelength 2	488 nm
Laser Wavelength 3	531 – 568 nm
Laser Wavelength 4	638 – 647 nm
Angle of Incidence	45 ± 1.5 degrees
Cone Half-angle	0.5 degrees
Optical Damage Rating	Not Tested
Flatness	Laser Flat
Steepness	Steep
Effective Index	1.8

Physical Filter Specifications (applies to standard sized parts; contact us regarding other sizes)

Specification	Value
Transverse Dimensions (L x W)	13.0 mm x 15.0 mm
Transverse Tolerance	+ 0.0 / - 0.2 mm
Filter Thickness (unmounted)	0.5 mm
Filter Thickness Tolerance (unmounted)	± 0.02 mm
Clear Aperture	≥ 80% (elliptical)
Scratch-Dig	40-20
Substrate Thickness (unmounted)	0.5 mm
Substrate Thickness Tolerance (unmounted)	± 0.02 mm
Orientation	Unmarked (reflective coating towards sample)